

L Number	Hits	Search Text	DB	Time stamp
95	55571	control near gate	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/04 14:39
97	1466709	memory	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/04 14:39
99	273487	source and drain	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/04 14:39
100	127944	(oxide near3 nitride near3 oxide) ONO (oxide-nitride-oxide) (oxide/nitride/oxide) (silicon near oxide/silicon near nitride/silicon near oxide)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/04 14:40
101	4263	(control near gate) and (source and drain) and memory and ((oxide near3 nitride near3 oxide) ONO (oxide-nitride-oxide) (oxide/nitride/oxide) (silicon near oxide/silicon near nitride/silicon near oxide))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/04 14:42